

Bifacial dye-sensitized solar cells with enhanced rear efficiency and power output

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Supplementary table and figures

Table S1 Output EIS parameters of the symmetric dummy cells employing various CEs. R_s : series resistance; R_{ct} : charge-transfer resistance; CPE: corresponding chemical capacitance; W : Nernst diffusion resistance; τ : lifetime of electrons in anode.

CEs	R_s ($\Omega \text{ cm}^2$)	R_{ct} ($\Omega \text{ cm}^2$)	W ($\Omega \text{ cm}^2$)	τ (μs)
Ru ₂ Se	10.60	5.40	5.73	28.17
RuSe	9.38	5.08	6.30	19.88
Ru _{0.5} Se	2.49	2.88	1.01	13.03
Ru _{0.33} Se	3.18	2.77	0.93	8.94
Ru _{0.25} Se	10.49	2.98	1.75	14.62
Ru _{0.2} Se	9.48	4.68	2.58	17.65
Se	9.81	154.90	4.90	93.18
Ru	15.32	893.30	7245	9947.18
Pt	20.77	7.23	0.83	85.11

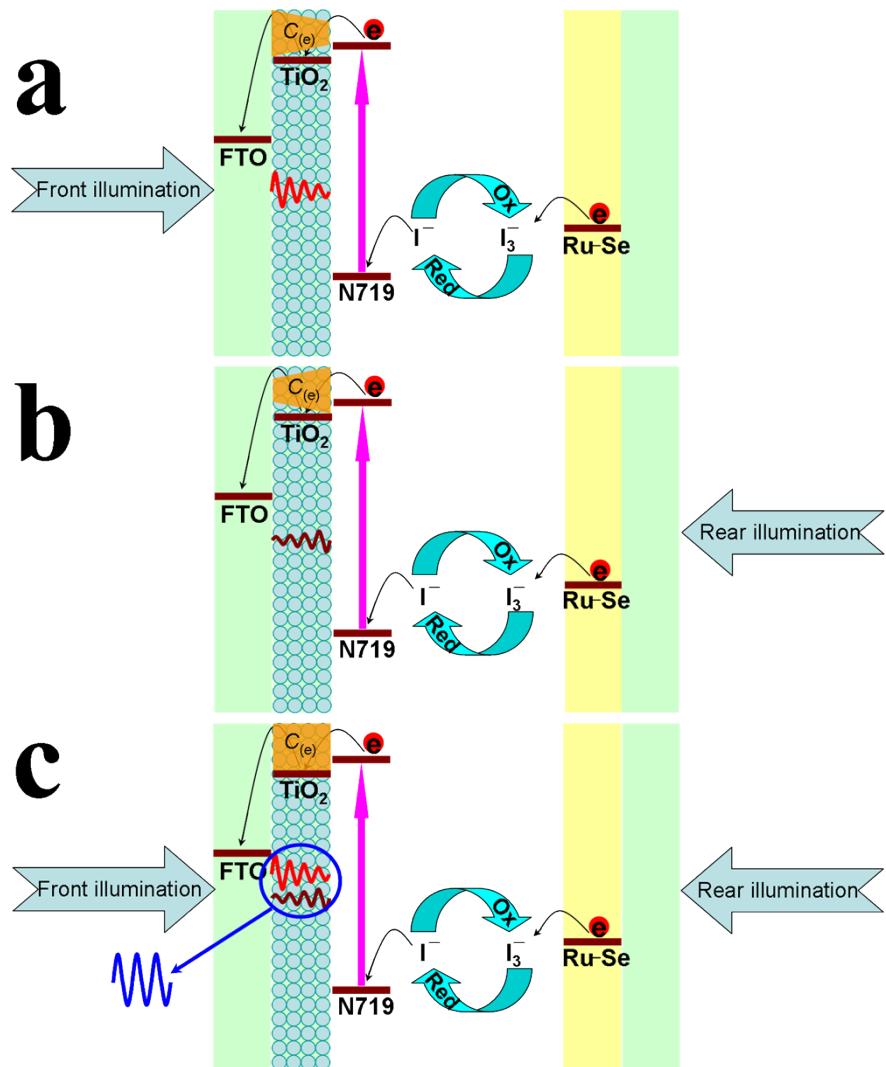


Fig. S1 Schemes representing incident light descent and electron density on conduction band of TiO_2 with irradiation from (a) front, (b) rear, and (c) both. The incident light intensity is controlled at 100 mW cm^{-2} (calibrated by a standard silicon solar cell) in either side.

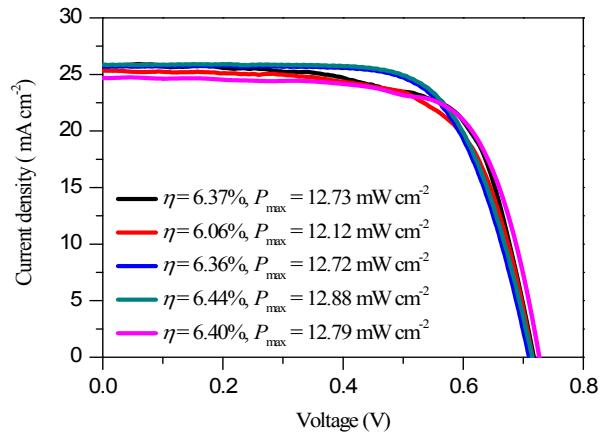


Fig. S2 Repeated characteristic J – V curves of the DSSCs employing $\text{Ru}_{0.33}\text{Se}$ alloy CE for both irradiation.

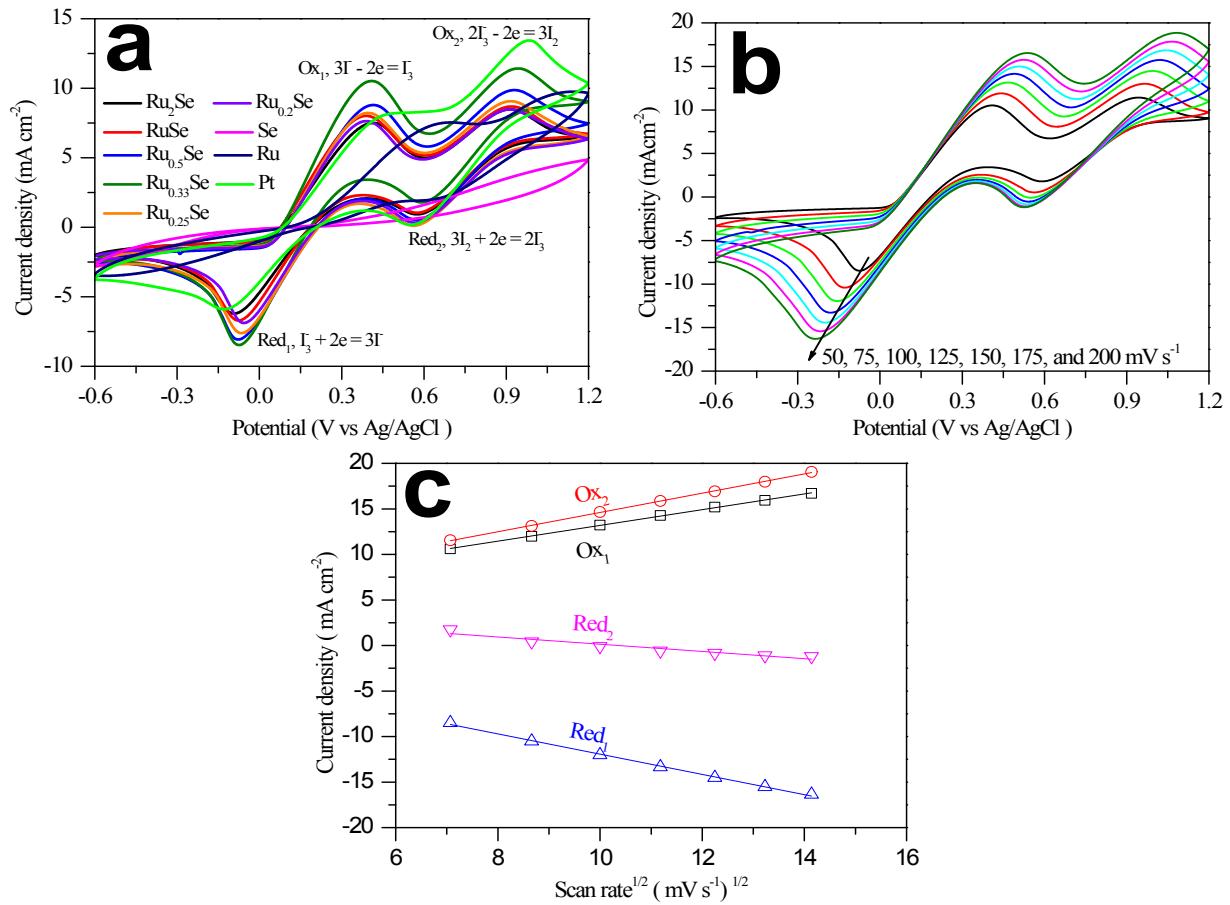


Fig. S3 (a) CV curves of various CEs recorded at a scan rate of 50 mV s⁻¹; (b) CV curves of Ru_{0.33}Se alloy CE at various scan rates; (c) Relationship between square root of potential and peak current density.

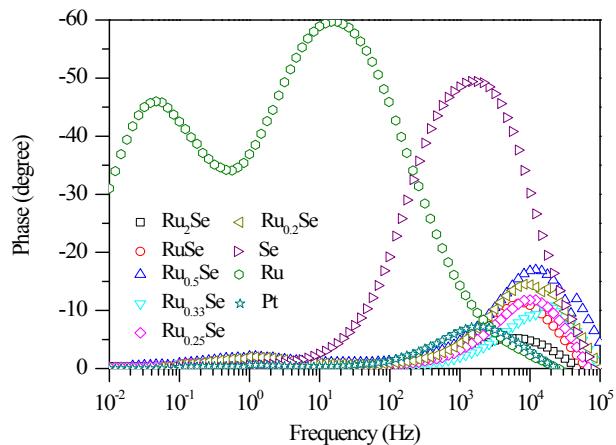


Fig. S4 Bode EIS spectra of the symmetric dummy cells from various CEs.